

FORM PTO-1449

U.S. DEPARTMENT OF
COMMERCE PATENT
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List of Information Cited by Applicant

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ATTY. DOCKET NO.

PSU 00 2182A

APPLICANT

NATAN ET AL

FILING DATE

JUNE 20, 2000

SERIAL NO.

09/598,395

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EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
AM	AA	5,547,748	08/1998 08/1996	Ruoff et al.	428	323	
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	AY	
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Arden Marsh

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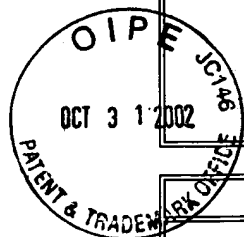
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Andin Masochel

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	AO	Al-Rawashdeh et al. (1998) J. Phys. Chem. B 102:361-371	X
	AP	Braun et al., Nature 402 (1999) 603-604	
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Jordan Mancoske

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Tierney